	n Note	

Application/Control No.	Applicant(s)/Patent under Reexamination
09/896,607	RINNE ET AL.
Examiner	Art Unit
Jude J. Jean-Gilles	2143

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	223 230-232	3/1/2006	JG
370	392 252	3/1/2006	JG
707	107	3/1/2006	JG

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
	1			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DA ⁻	TE E	XMR
PAM tool: Effective Filing Date Double Patenting	3/1/2	006	JG
EAST Tool: USPAT EPO JPO DERWENT IBM_TDB	3/1/2	006	JG
Internet tool: google.com NPL's IEEE	3/1/2	006	JG

